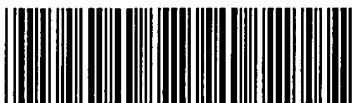


Search Notes

Application/Control No.

10/671,678

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

AOKI, YASUSHI

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	52,55,57, 63,65,89, 560-563	3/1/2005	HLN
330	252,253	—	—
330	269	—	—

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	3/1/2005	HLN